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Commission on Powder Diffraction

At its 14 August 1987 meeting in Perth, the General Assembly of the IUCr established a Commission on Powder Diffraction. This is an action widely welcomed and considered by many to be long overdue.

In early 1986, the IUCr Executive Committee established an *ad hoc* committee to assess world-wide interest and, if it be sufficient, to prepare specific proposals for the General Assembly to consider in determining whether to establish a Commission on Powder Diffraction. The Terms of Reference proposed by the committee and the Executive Committee and accepted by the General Assembly are:

i. To advise the IUCr in organizing or sponsoring meetings, schools and Congress sessions on powder diffraction and related subjects.

ii. To promote and coordinate scientific exchange between countries in the field of powder diffraction.

iii. To cooperate with other IUCr Commissions on matters concerning powder diffraction.

iv. To cooperate with other international bodies interested in powder diffraction and allied subjects.

v. To promote useful interactions of the IUCr with the large world-wide body of X-ray and neutron powder diffractionists.

vi. To promote the scientific growth and development of the field of powder diffraction.

Since the members of the *ad hoc* committee became the initial members of the Commission, they were able to meet three times during the Congress to make plans for Commission projects. Among those being given first consideration are Program exchange 'bank'.

Satellite meeting for the 1990 Bordeaux Congress.

Workshop on the Rietveld method (to be held between August 1988 and August 1989).

Newsletter.

Round-robin with the Rietveld method involving both X-ray and neutron data and several samples.

New book(s), possibly resulting from workshop(s).

Powder diffraction sessions at 1990 IUCr Congress at Bordeaux.

The members of the new Commission on Powder Diffraction are:

R. A. Young	USA (Chairman)
Z. Bojarski	Poland
R. J. Hill	Australia
A. W. Hewat	France
J. I. Langford	UK (Secretary)
PE. Werner	Sweden
T. Yamanaka	Japan.

In addition, Dr L. Frevel serves as the JCPDS-appointed representative to the Commission.

Notes and News

Announcements and other items of crystallographic interest will be published under this heading at the discretion of the Editorial Board. The notes (in duplicate) should be sent to the Executive Secretary of the International Union of Crystallography (J. N. King, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England).

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Standard Crystallographic File Structure-87

How often have you been frustrated by finding that your datafile was in the wrong format for your program? And how much time have you spent in writing conversion programs to change data from one format to another?

In order to minimize these problems, the Data and Computing Commissions of the International Union of Crystallography approved, in 1981, a Standard Crystallographic File Structure (*Acta Cryst.* A39, 216–224). This describes a file structure that can be used to store or transfer most kinds of crystallographic data and, at the same time, is easy to program and is adaptable to individual users needs. Since 1981 the standard has been enhanced and in the most recent release (SCFS-87) it can include all the information (including text. tables and supplementary material) required for a short structural paper in *Acta Crystallographica* including the text. It is designed not only for giving structural data, but it can also include data as different as powder patterns and protein derivative structure factors.

Copies of the latest standard can be obtained from: Dr I. D. Brown, Institute for Materials Research, McMaster University, Hamilton, Ontario, Canada L8S 4M1. 1002332@mcmaster.netnorth

It is available in either hardcopy form or as a machine-readable file which may be sent over the NetNorth/Bitnet/Earn networks. A user-adaptable program to read an SCFS-87 file is available by network from: Dr H. D. Flack, Laboratoire de Cristallographie, Université de Genève, 24 quai Ernest-Ansermet, 1211 Genève4, Switzerland. "flack@cgeuge52"

New Commercial Products

Announcements of new commercial products are published by the Journal of Applied Crystallography free of charge. The descriptions, up to 300 words or the equivalent if a figure is included, should give the price and the manufacturers full address. Full or partial inclusion is subject to the Editor's approval and to the space available. All correspondence should be sent to the Editor, Professor M. Schlenker, Editor Journal of Applied Crystallography. Laboratoire Louis Néel du CNRS, BP166, F-38042 Grenoble CEDEX, France. The International Union of Crystallography can as-

The International Union of Crystallography can assume no responsibility for the accuracy of the claims made. A copy of the version sent to the printer is sent to the company concerned. J. Appl. Cryst. (1987). 20, 538

PL6100 Fourier Transform Photoluminescence Spectrometer

Photoluminescence spectroscopy is a well established technique for the characterization of impurities, crystal defects and dopants, such as the simultaneous assessment of both boron and phosphorus in silicon. Until recently, the conventional method for these measurements has been based on dispersive optical technology using a monochromator. These systems suffer from restricted sensitivity and long measurement times.

Fourier transform spectroscopy has been used intermittently for more than 20 years for photoluminescence measurement and its advantages are well known. Now the development of a high performance low-cost near-infrared Fourier transform spectrometer by Bio-Rad has led to the PL6100, a state of the art, highsensitivity system.

The PL6100 Fourier Transform Photoluminescence Spectrometer illuminates the samples, which are mounted in a liquid-helium cryostat, with an argon ion laser. The optical performance of the system is such that greater than 15000 times signal-to-noise improvement is obtained over conventional systems using a monochromator enabling very weak spectral features to be observed. In addition, the use of a Fourier transform spectrometer enables measurement times to be reduced to typically 120 times less than with conventional equipment.

The software for the PL6100 is full menu-driven with a HELP key to guide the user.

Bio-Rad MicroScience, 53–63 Greenhill Crescent, Watford Business Park, Watford, Herts WD1 8QS, England

Books Received

The following book has been received by the Editor. Briel and generally uncritical notices are given of works of marginal crystallographic interest; occasionally a book of fundamental interest is included under this heading because of difficulty in finding a suitable reviewer without great delay.

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Defect crystal chemistry and its applications. By R. J. D. Tilley. Pp. viii + 236. Glasgow and London: Blackie; USA: Chapman & Hall, 1987. Price £35.00. A review of this book, by A. A. Urusovskaya. has been published in the November 1987 issue of *Acta Crystallographica* Section A, page 840.